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FORM:	PTO-1449
(REV:	7-80)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

Atty Docket No: Serial No: 94-0280.03

Applicant:

Thomas A. Figura et al.

Filing Date: 12/22/99

Group:

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(37 CFR 1.98(b))

(use several sheets if necessary)

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	AE	5,476,817	12/19/95	Numata	437	195
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4	BE	Tetsuo Ono, Ryoji Hamasaki and Tatsumi Mizutani, "Mechanism for CF Polymer Film Deposition through Deep Sion Holes in Electron Cyclotron Resonance Plasma," Jpn. J. Appl. Phys. Vol. 35, pp. 2468-2471, Part 1, No. 4B, April 1996.							
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EXAMINER:

Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.

FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 94-0280.03	Serial No: 09/471,460
INFORMATION I	DISCLOSURE STATEMENT BY APPLICANT	Applicant: Thomas A. Figura et al	
(37 CFR 1.98(b))	(use several sheets if necessary)	Filing Date: 12/22/99	Group: 2812

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